

LICENSING OPPORTUNITY

GATELESS P- N JUNCTION METROLOG

Patent 11,474,134

DESCRIPTION

Problem:

We have solved the issue of using standard metal electrical contacts for connecting multiple devices composed of the same material.

Invention:

We provide the process of building a special device for resistance metrology that allows one to output many different quantum resistances (like a variable resistor).

BENEFITS

Commercial Application:

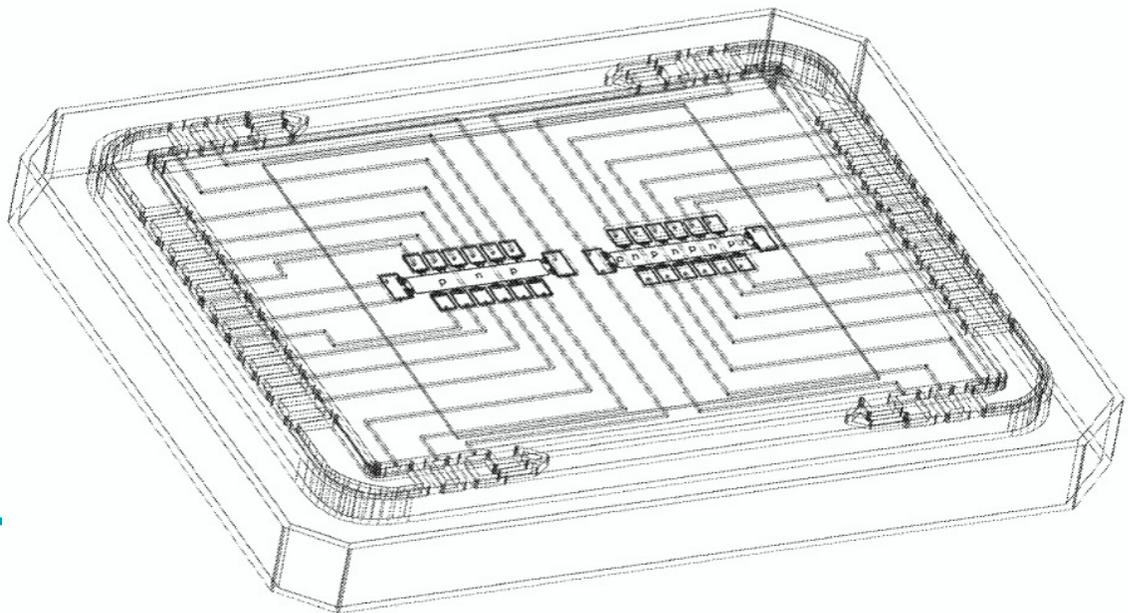
Calibration services

Competitive Advantages:

Having such a system using a chip based on this process would allow one to calibrate resistors that have many different values as opposed to being able to calibrate at one value.

Eliminate your bulky equipment.

Improve your resistance uncertainty.



A plan view of the gateless P-N junction metrolog

CONTACT

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